

WHAT IS CLAIMED IS:

1. An analysis apparatus comprising: a measurement head for measuring sample characteristics;

a calibration conditions file comprising at least one calibration condition made by carrying out device calibration for the measurement head in advance;

designation means for designating one of the calibration conditions within the calibration conditions file;

a measurement sequence comprising a sequence for a plurality of measurement steps comprising measurement conditions for carrying out measurements and calibration conditions designated by the designation means; and

measurement means for referring to each measurement step of the measurement sequence and carrying out measurement after inputting measurement conditions and calibration conditions for each measurement step to the measurement head.

2. The analysis apparatus according to claim 1, further comprising means for saving calibration conditions made by carrying out device calibration on the measurement head in advance as a file in the calibration conditions file and designating calibration conditions used in each measurement step in the measurement sequence using a calibration conditions file name.

3. The analysis apparatus according to claim 1, characterized by a thermal analysis apparatus equipped with

a furnace for heating a sample at the measurement head and measuring physical characteristics of the sample while changing temperature.

4. The analysis apparatus according to claim 2, characterized by a thermal analysis apparatus equipped with a furnace for heating a sample at the measurement head and measuring physical characteristics of the sample while changing temperature.